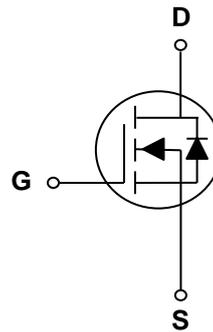


General Description

These N-Channel enhancement mode power field effect transistors are using SGT technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features

V_{DS}	30V
I_D (at $V_{GS}=10V$)	170A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	1.3m Ω (Typ)

PDFN5x6

Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	TC=25 $^{\circ}C$	I_D	170 A
	TC=100 $^{\circ}C$	I_D	107 A
Maximum Power Dissipation	P_D	95	W
Single pulse avalanche energy	E_{AS}	245	mJ
Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	$^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal Resistance junction-case	$R_{\theta Jc}$		1.3	$^{\circ}C/W$
Thermal Resistance junction-to-Ambient	$R_{\theta JA}$		62	$^{\circ}C/W$

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30V, V_{GS}=0V$			1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$			± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.6	2.5	V
$R_{DS(ON)}$	Drain-Source On-State Resistance	$V_{GS}=10V, I_D=50A$		1.3	1.6	m Ω
		$V_{GS}=4.5V, I_D=50A$		1.9	2.5	m Ω
DYNAMIC PARAMETERS						
C_{ISS}	Input Capacitance	$V_{DS}=15V, V_{GS}=0V,$ $F=1.0MHz$		3050		pF
C_{OSS}	Output Capacitance			1300		pF
C_{RSS}	Reverse Transfer Capacitance			28		pF
SWITCHING PARAMETERS						
$t_{d(on)}$	Turn-on Delay Time	$V_{GS}=10V$ $V_{DS}=15V$ $I_D=1.0A$ $R_{GEN}=3.3\Omega$		11		nS
t_r	Turn-on Rise Time			39		nS
$t_{d(off)}$	Turn-Off Delay Time			33		nS
t_f	Turn-Off Fall Time			9		nS
Q_g	Total Gate Charge	$V_{DS}=15V, I_D=20A,$ $V_{GS}=10V$		41		nC
Q_{gs}	Gate-Source Charge			8		nC
Q_{gd}	Gate-Drain Charge			6.5		nC
V_{SD}	Diode Forward Voltage	$V_{GS}=0V, I_{SD}=1A$		0.7	1.3	V
R_g	Gate resistance	$V_{GS}=0V, V_{DS}=0V,$ $F=1MHz$		1.5		Ω

Note:

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
3. Essentially independent of operating temperature.
4. $V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=68A, R_G=25\Omega, Starting T_J=25^\circ C$.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

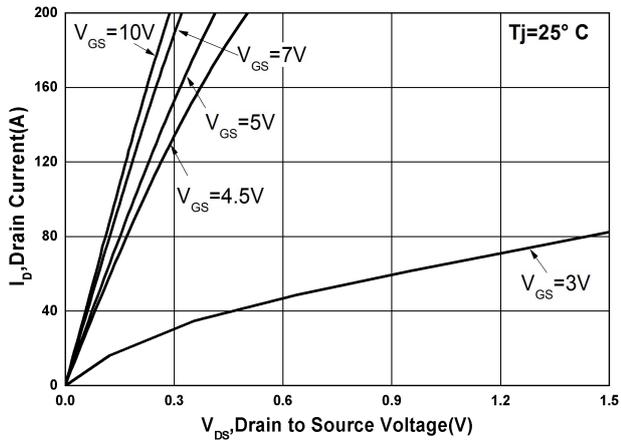


Figure 1: Typical Output Characteristic

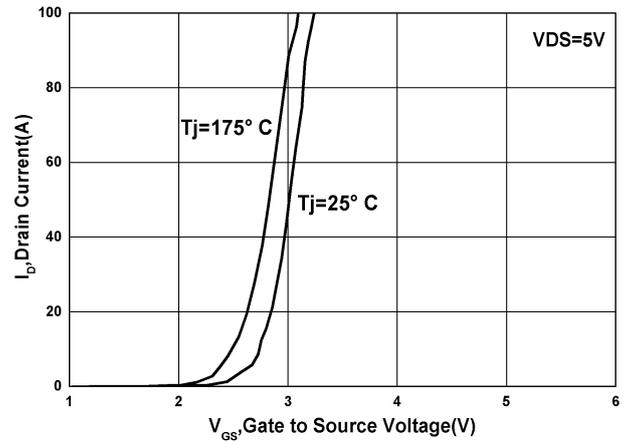


Figure 2: Typical Transfer Characteristics

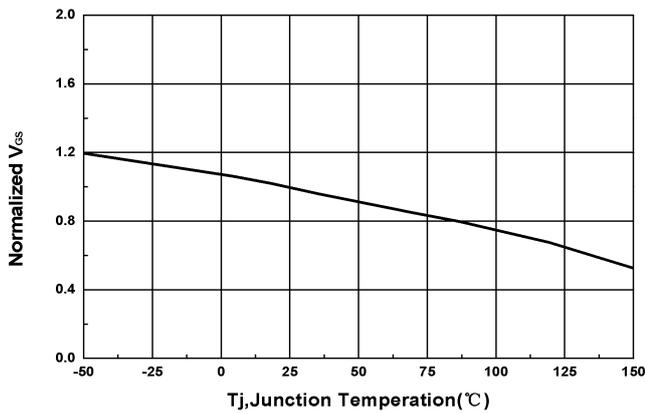


Figure 3: Normalized VGS vs Tj

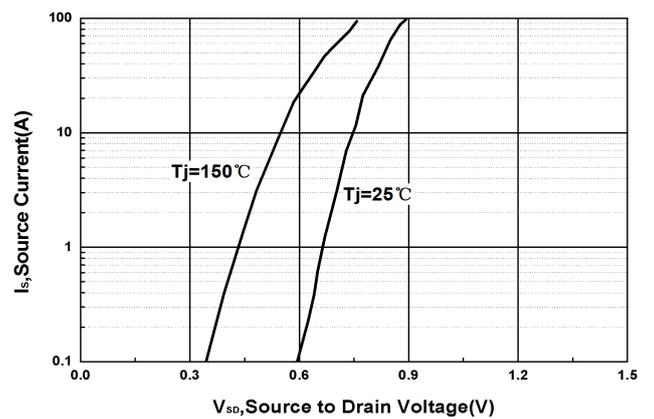


Figure 4: IS vs VSD

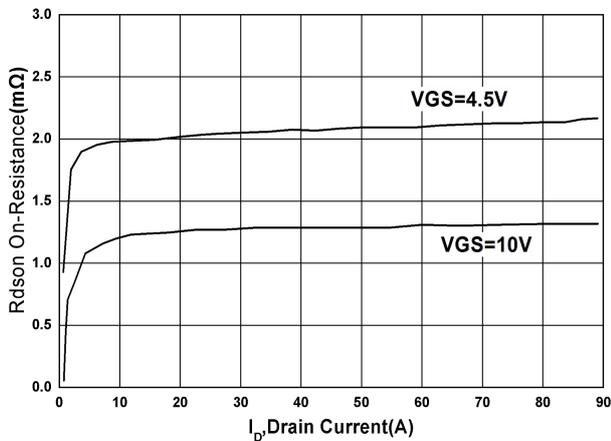


Figure 5: Rdson vs ID

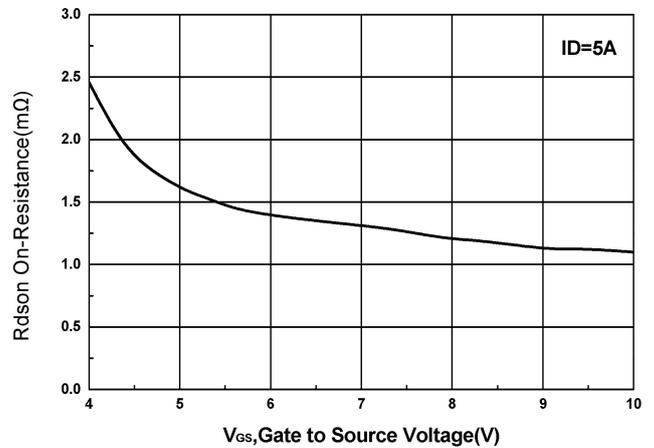


Figure 6: Rdson vs VGS

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

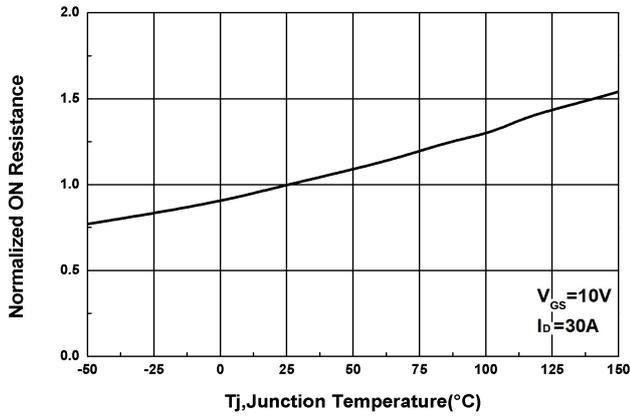


Figure 7: Normalized Rdson vs Tj

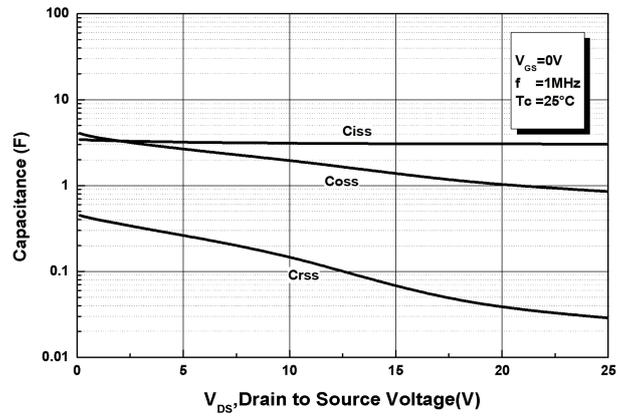


Figure 8: Capacitance vs. VDS

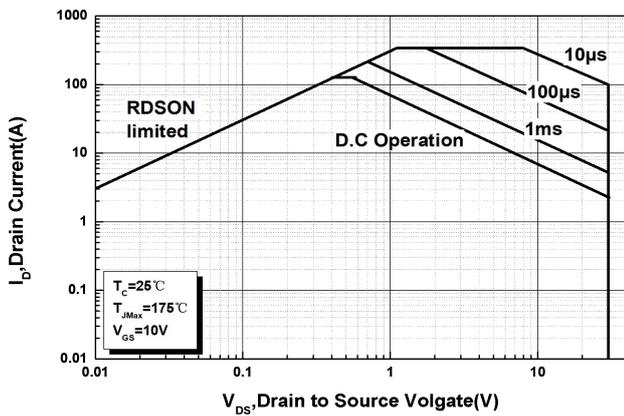


Figure 9: Maximum Forward Biased Safe Operating Area

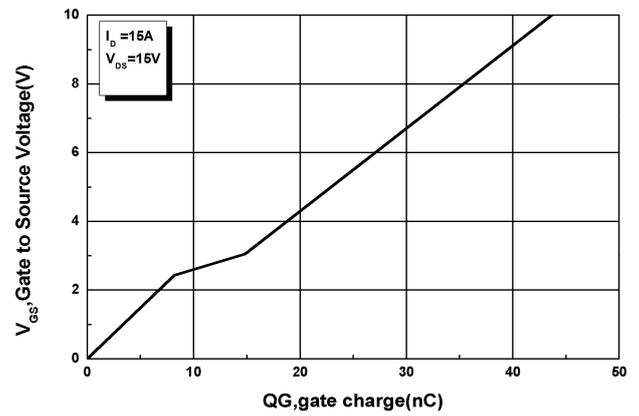


Figure 10: Gate Charge Characteristics

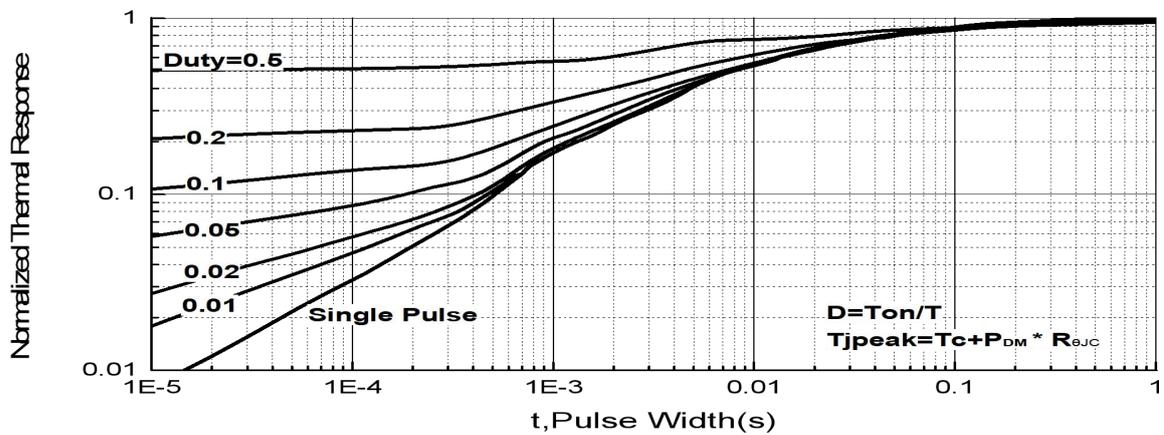
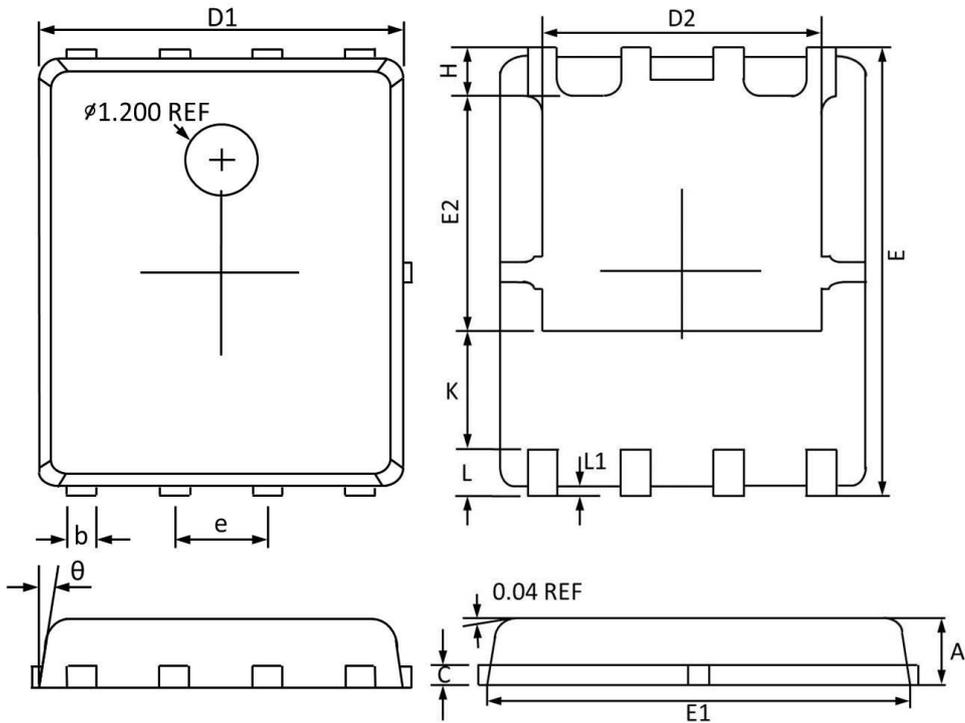


Figure 11: Normalized Thermal Response

PDFN5x6 PACKAGE INFORMATION



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	MAX	MIN	MAX	MIN
A	1.100	0.800	0.043	0.031
b	0.510	0.330	0.020	0.013
C	0.300	0.200	0.012	0.008
D1	5.100	4.800	0.201	0.189
D2	4.100	3.610	0.161	0.142
E	6.200	5.900	0.244	0.232
E1	5.900	5.700	0.232	0.224
E2	3.780	3.350	0.149	0.132
e	1.27BSC		0.05BSC	
H	0.700	0.410	0.028	0.016
K	1.500	1.100	0.059	0.043
L	0.710	0.510	0.028	0.020
L1	0.200	0.060	0.008	0.002
θ	12°	0°	12°	0°